256K X 8 BIT LOW POWER CMOS SRAM

FEATURES

Access time: 55ns
Low power consumption:
Operating current: 20mA (TYP.)

Standby current : 20mA(TYP.)L Version

1μ A (TYP.) LL-version

■ Single 2.7V ~ 3.6V power supply

■ Fully static operation

■ Tri-state output

■ Data retention voltage : 1.5V (MIN.)

All Products ROHS Compliant

■ Package: 32-pin 450 mil SOP

32-pin 8mm x 20mm TSOP-I 32-pin 8mm x 13.4mm sTSOP 36-ball 6mm x 8mm TFBGA

GENERAL DESCRIPTION

The AS6C2008 is a 2,097,152-bit low power CMOS static random access memory organized as 262,144 words by 8 bits. It is fabricated using very high performance, high reliability CMOS technology. Its standby current is stable within the range of operating temperature.

The AS6C2008 is well designed for very low power system applications, and particularly well suited for battery back-up nonvolatile memory application.

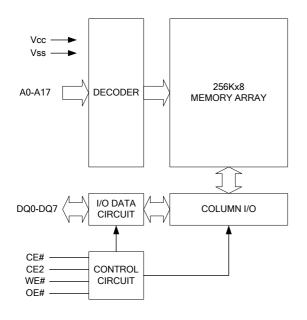
The AS6C2008 operates from a single power supply of $2.7V \sim 3.6V$

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PRODUCT FAMILY

Product	Operating	Vcc Range	Speed	Speed Power Dissipation			
Family	Temperature	vcc range	Оресси	Standby(IsB1,TYP.)	Operating(Icc,TYP.)		
AS6C2008 (I)	-40 ~ 85°C	2.7 ~ 3.6V	55ns	20μA(L)/1μA(LL)	20mA		

FUNCTIONAL BLOCK DIAGRAM

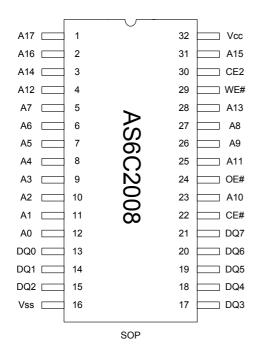


PIN DESCRIPTION

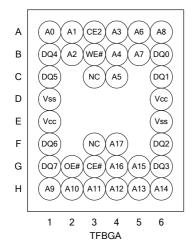
SYMBOL	DESCRIPTION
A0 - A17	Address Inputs
DQ0 – DQ7	Data Inputs/Outputs
CE#, CE2	Chip Enable Inputs
WE#	Write Enable Input
OE#	Output Enable Input
Vcc	Power Supply
Vss	Ground
NC	No Connection

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PIN CONFIGURATION







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ABSOLUTE MAXIMUM RATINGS*

PARAMETER	SYMBOL	RATING	UNIT
Terminal Voltage with Respect to Vss	VTERM	-0.5 to 4.6	V
Operating Temperature	Та	-40 to 85(I grade)	°C
Storage Temperature	Тѕтс	-65 to 150	°C
Power Dissipation	PD	1	W
DC Output Current	Іоит	50	mA
Soldering Temperature (under 10 sec)	Tsolder	260	°C

^{*}Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to the absolute maximum rating conditions for extended period may affect device reliability.

TRUTH TABLE

MODE	CE#	CE2	OE#	WE#	I/O OPERATION	SUPPLY CURRENT
Standby	Н	Х	Х	Х	High-Z	Isb,Isb1
Stariuby	Х	L	Х	Х	High-Z	ISB,ISB1
Output Disable	L	Н	Н	Н	High-Z	lcc,lcc1
Read	L	Н	L	Н	D оит	Icc,Icc1
Write	L	Н	Х	L	Din	lcc,lcc1

Note: H = VIH, L = VIL, X = Don't care.

DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDI	MIN.	TYP. *4	MAX.	UNIT	
Supply Voltage	Vcc			2.7	3.0	3.6	V
Input High Voltage	Vih ^{*1}			2.2	-	Vcc+0.3	V
Input Low Voltage	V _{IL} *2			- 0.2	-	0.6	V
Input Leakage Current	ILI	$V_{CC} \ge V_{IN} \ge V_{SS}$		- 1	-	1	μA
Output Leakage Current	ILO	$V_{CC} \ge V_{OUT} \ge V_{SS}$, Output Disabled	$V_{CC} \ge V_{OUT} \ge V_{SS}$,		-	1	μA
Output High Voltage	Vон	I _{OH} = -1mA	2.2	2.7	-	V	
Output Low Voltage	Vol	I _{OL} = 2mA		-	1	0.4	V
Average Operating	Icc	Cycle time = Min. CE# = V _{IL} and CE2 : I _{I/O} = 0mA	= V _{IH} , <u>- 55</u>	-	20	35	mA
Average Operating Power supply Current	lcc1	Cycle time = 1μ s CE# \leq 0.2V and CE2 \geq Vcc-0.2V, I _{I/O} = 0mA other pins at 0.2V or Vcc-0.2V		, -	4	5	mA
	Isa	CE# = V _{IH} or CE2 =	VIL	-	0.3	0.5	mA
Standby Power Supply Current	ISB1	CE# \ge V _{CC} -0.2V or CE2 \le 0.2V	- - - *		4	20*5	μA

*I= Industrial temperature



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Notes:

- 1. $V_{IH}(max) = V_{CC} + 3.0V$ for pulse width less than 10ns.
- 2. VIL(min) = Vss 3.0V for pulse width less than 10ns.
- 3. Over/Undershoot specifications are characterized, not 100% tested.
- 4. Typical values are included for reference only and are not guaranteed or tested. Typical valued are measured at V_{CC} = V_{CC} (TYP.) and T_A = 25 $^{\circ}$ C
- 5. 10µA for special request

CAPACITANCE (TA = 25° C, f = 1.0MHz)

PARAMETER	SYMBOL	MIN.	MAX	UNIT
Input Capacitance	Cin	-	6	pF
Input/Output Capacitance	Ci/o	-	8	pF

Note: These parameters are guaranteed by device characterization, but not production tested.

AC TEST CONDITIONS

Input Pulse Levels	0.2V to Vcc - 0.2V
Input Rise and Fall Times	3ns
Input and Output Timing Reference Levels	1.5V
Output Load	$C_L = 30pF + 1TTL$, $I_{OH}/I_{OL} = -1mA/2mA$

AC ELECTRICAL CHARACTERISTICS

(1) READ CYCLE

PARAMETER	SYM		AS6C	AS6C2008-55		UN	
			MIN	MAX.			
Read Cycle Time	trc		55	-			ns
Address Access Time	taa		-	55			ns
Chip Enable Access Time	tace		-	55			ns
Output Enable Access Time	toe		-	30			ns
Chip Enable to Output in Low-Z	tcLz*		10	-			ns
Output Enable to Output in Low-Z	toLz*		5	-			ns
Chip Disable to Output in High-Z	tcHz*		-	20			ns
Output Disable to Output in High-Z	tonz*		-	20			ns
Output Hold from Address Change	tон		10	-			ns

(2) WRITE CYCLE

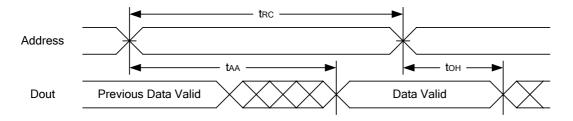
PARAMETER	SYM		AS6C	2008-55		UNIT
			MIN	MAX.		
Write Cycle Time	twc		55	-		ns
Address Valid to End of Write	taw		50	-		ns
Chip Enable to End of Write	tcw		50	-		ns
Address Set-up Time	tas		0	-		ns
Write Pulse Width	twp		45	-		ns
Write Recovery Time	twr		0	-		ns
Data to Write Time Overlap	tow		25	-		ns
Data Hold from End of Write Time	tон		0	-		ns
Output Active from End of Write	tow*		5	-		ns
Write to Output in High-Z	twnz*		-	20		ns

^{*}These parameters are guaranteed by device characterization, but not production tested.

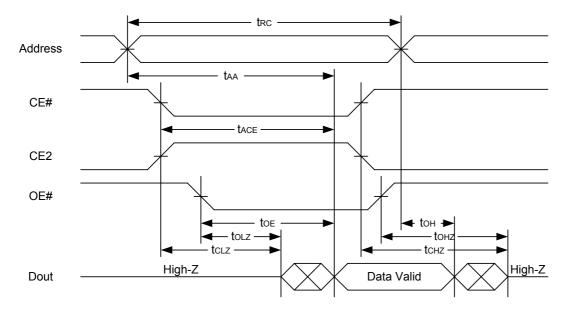
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TIMING WAVEFORMS

READ CYCLE 1 (Address Controlled) (1,2)



READ CYCLE 2 (CE# and CE2 and OE# Controlled) (1,3,4,5)

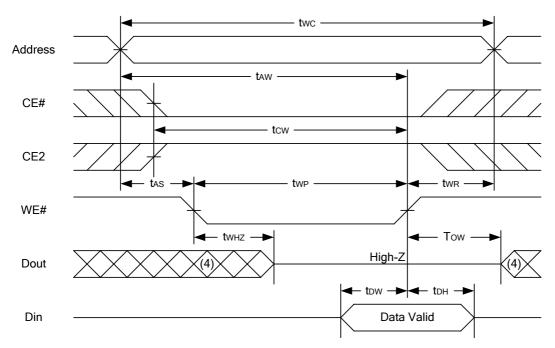


Notes :

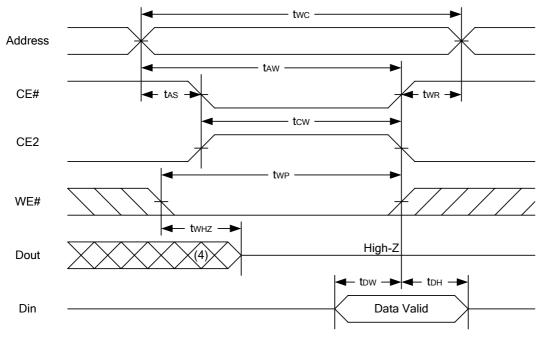
- 1.WE# is high for read cycle.
- 2.Device is continuously selected OE# = low, CE# = low., CE2 = high.
- 3.Address must be valid prior to or coincident with CE# = low, CE2 = high; otherwise tAA is the limiting parameter.
- 4.tclz, tolz, tchz and tohz are specified with CL = 5pF. Transition is measured ±500mV from steady state.
- 5.At any given temperature and voltage condition, t_{CHZ} is less than t_{CLZ} , t_{OHZ} is less than t_{OLZ} .

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WRITE CYCLE 1 (WE# Controlled) (1,2,3,5,6)



WRITE CYCLE 2 (CE# and CE2 Controlled) (1,2,5,6)



Notes:

- 1.WE#, CE# must be high or CE2 must be low during all address transitions.
- 2.A write occurs during the overlap of a low CE#, high CE2, low WE#.
- 3.During a WE#controlled write cycle with OE# low, twp must be greater than twnz + tow to allow the drivers to turn off and data to be placed on the bus
- 4. During this period, I/O pins are in the output state, and input signals must not be applied.
- 5.If the CE#low transition and CE2 high transition occurs simultaneously with or after WE# low transition, the outputs remain in a high impedance state.
- 6.tow and twHZ are specified with C_L = 5pF. Transition is measured $\pm 500mV$ from steady state.

Rev. 1.1 256K X 8 BIT LOW POWER CMOS SRAM

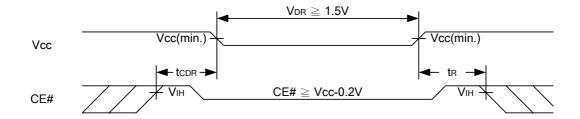
DATA RETENTION CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Vcc for Data Retention		$\begin{array}{l} \text{CE\#} \geq \text{V}_{\text{CC}} \text{- } 0.2\text{V} \\ \text{or CE2} \leq 0.2\text{V} \end{array}$	1.5	-	3.6	V
	_	V _{CC} = 1.5V				
Data Retention Current		$CE# \ge V_{CC} - 0.2V$ -				
		or CE2 \leq 0.2V	-	0.5	10	μA
Chip Disable to Data	tcpr	See Data Retention	0	_	_	ns
Retention Time	LCDK	Waveforms (below)		_	_	113
Recovery Time	t R		t RC∗	-	-	ns

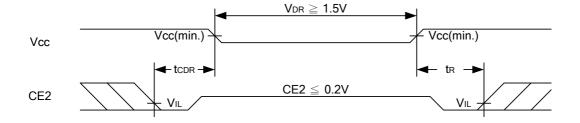
tRC∗ = Read Cycle Time **I= Industrial temperature

DATA RETENTION WAVEFORM

Low Vcc Data Retention Waveform (1) (CE# controlled)

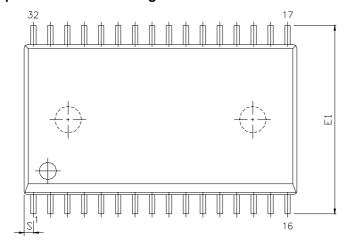


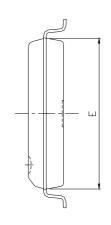
Low Vcc Data Retention Waveform (2) (CE2 controlled)

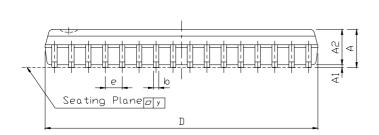


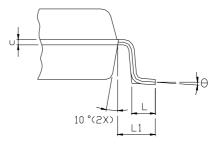
PACKAGE OUTLINE DIMENSION

32 pin 450 mil SOP Package Outline Dimension





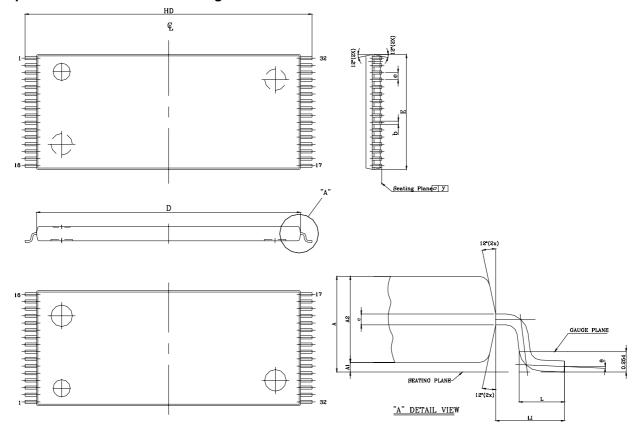




SYM. UNIT	INCH.(BASE)	MM(REF)
Α	0.118 (MAX)	2.997 (MAX)
A1	0.004(MIN)	0.102(MIN)
A2	0.111(MAX)	2.82(MAX)
b	0.016(TYP)	0.406(TYP)
С	0.008(TYP)	0.203(TYP)
D	0.817(MAX)	20.75(MAX)
E	0.445 ±0.005	11.303 ±0.127
E1	0.555 ±0.012	14.097 ±0.305
е	0.050(TYP)	1.270(TYP)
L	0.0347 ±0.008	0.881 ±0.203
L1	0.055 ±0.008	1.397 ±0.203
S	0.026(MAX)	0.660 (MAX)
у	0.004(MAX)	0.101(MAX)
Θ	0° -10°	0° -10°

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32 pin 8mm x 20mm TSOP-I Package Outline Dimension

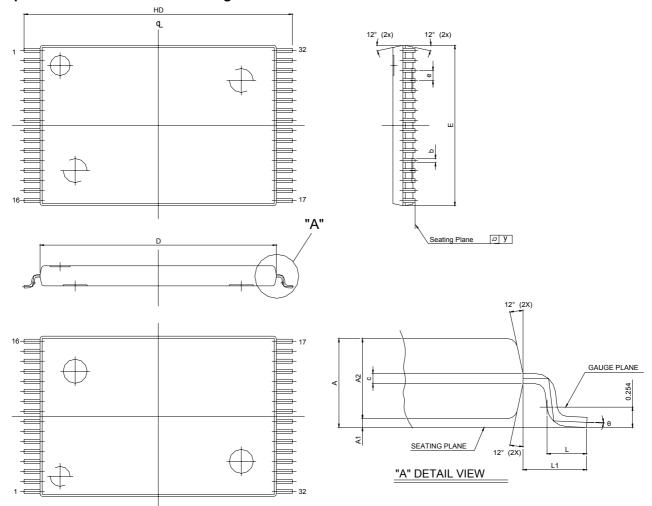


SYM. UNIT	INCH(BASE)	MM(REF)
Α	0.047 (MAX)	1.20 (MAX)
A1	0.004 ±0.002	0.10 ±0.05
A2	0.039 ±0.002	1.00 ±0.05
b	0.008 + 0.002 - 0.001	0.20 + 0.05 -0.03
С	0.005 (TYP)	0.127 (TYP)
D	0.724 ±0.004	18.40 ±0.10
E	0.315 ±0.004	8.00 ±0.10
е	0.020 (TYP)	0.50 (TYP)
HD	0.787 ±0.008	20.00 ±0.20
L	0.0197 ±0.004	0.50 ±0.10
L1	0.0315 ±0.004	0.08 ±0.10
у	0.003 (MAX)	0.076 (MAX)
Θ	0°∼5°	0°~5°

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Rev. 1.1

32 pin 8mm x 13.4mm sTSOP Package Outline Dimension

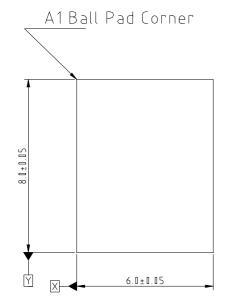


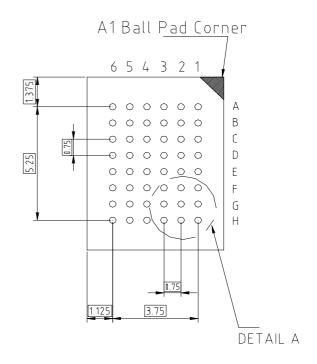
SYM. UNIT	INCH(BASE)	MM(REF)
Α	0.049 (MAX)	1.25 (MAX)
A1	0.005 ±0.002	0.130 ±0.05
A2	0.039 ±0.002	1.00 ±0.05
b	0.008 ±0.01	0.20±0.025
С	0.005 (TYP)	0.127 (TYP)
D	0.465 ±0.004	11.80 ±0.10
E	0.315 ±0.004	8.00 ±0.10
е	0.020 (TYP)	0.50 (TYP)
HD	0.528±0.008	13.40 ±0.20.
L	0.0197 ±0.004	0.50 ±0.10
L1	0.0315 ±0.004	0.8 ±0.10
у	0.003 (MAX)	0.076 (MAX)
Θ	0°∼5°	0°∼5°

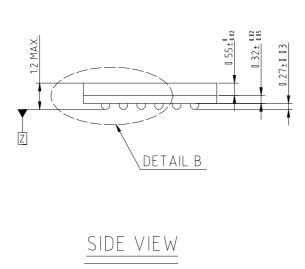
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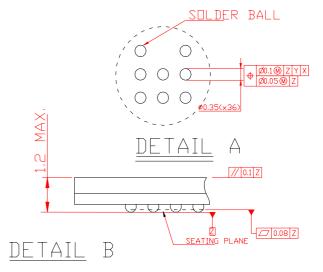
Rev. 1.1

36 ball 6mm × 8mm TFBGA Package Outline Dimension











256K X 8 BIT LOW POWER CMOS SRAM

ORDERING INFORMATION

Ordering Codes

				Operating	Speed
Alliance	Organization	VCC range	Package	Temp	ns
				Industrial ~	
AS6C2008-55SIN	256K X 8	2.7-3.6V	32pin 450mil SOP	-40°C to 85° C	55
				Industrial ~	
AS6C2008-55TIN	256K X 8	2.7-3.6V	32pin TSOP-I (8 x 20 mm)	-40°C to 85° C	55
				Industrial ~	
AS6C2008-55STIN	256K X 8	2.7-3.6V	32pin sTSOP (8 x 13.4 mm)	-40°C to 85° C	55
				Industrial ~	
AS6C2008-55BIN	256K X 8	2.7-3.6V	36pin TFBGA (6mm x 8mm)	-40°C to 85° C	55

Part numbering system

AS6C	2008	- 55	X	X	N				
			Package Options:	Temperature Range:					
low	Device		S = 32 pin 450 mil SOP	I = Industrial	N = Lead				
power	Number		T = 32 pin TSOP 1 (8mm x 20 mm)	(-40° to +85° C)	Free ROHS				
SRAM	20 = 2M	Access	ST = 32 pin sTSOP (8 x 13.4 mm)	,	Compliant				
prefix	08 = by 8	Time	B = 36 ball 6 x 8mm TFBGA		Part				

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